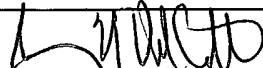


INFORMATION DISCLOSURE CITATION PTO-1449 Sheet 1 of 1			Complete If Known	
			Application Number	10/060,109
			Filing Date	January 28, 2002
			First Named Inventor	Patel et al.
			Art Unit	1746
			Examiner Name	Delcotto, Gregory R.
			Attorney Docket Number	60937-0129

U.S. PATENT DOCUMENTS						
Examiner Initials	Document Number Number - Kind Code ¹	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Class	Subclass	Filing Date if Appropriate

FOREIGN PATENT DOCUMENTS							
Examiner Initials	Foreign Patent Document Country Code ² - Number ³ - Kind Code ⁴ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Class	Subclass	Translation	
						Yes	No
h0	WO 01/27986	04/19/2001	Gebrüder Decker GMBH & Co. KG	—	—	x	

OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS	
Examiner Initials	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published

Examiner Signature		Date Considered	7/25/04
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¹ See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ² Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ³ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁴ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁵ Applicant is to place a check mark here if English language Translation is attached.

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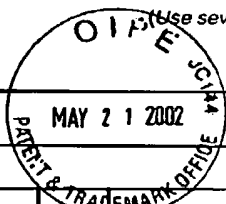
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							YES	NO
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AD	BO	Baklanov, et al., "Applicability of HF Solutions for Contact Hole Cleaning on Top of TiSi ₂ ," Electrochemical Society Proceedings, Vol. 97-35, pp. 602-609 (1998)
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A. J. [Signature]

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	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO
<i>AD</i>	BZ	International Search Report from PCT/US02/03233	04/17/2003	PCT	—	—	
<i>20</i>	CA	WO 92/04942	04/02/1992	PCT	—	—	
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